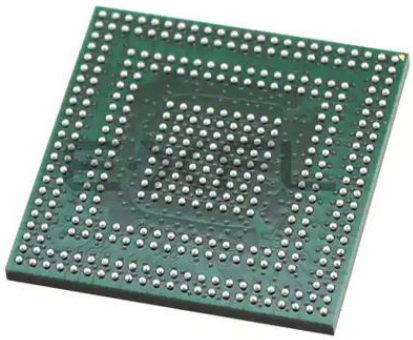

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e300c3
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	133MHz
Co-Processors/DSP	Communications; QUICC Engine
RAM Controllers	DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100Mbps (3)
SATA	-
USB	USB 2.0 (1)
Voltage - I/O	1.8V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	369-LFBGA
Supplier Device Package	369-PBGA (19x19)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/ppc8306svmabdca

2.1.3 Output Driver Characteristics

The following table provides information on the characteristics of the output driver strengths.

Table 3. Output Drive Capability

Driver Type	Output Impedance (Ω)	Supply Voltage (V)
Local bus interface utilities signals	42	OV_{DD} = 3.3
DDR2 signal	18	GV_{DD} = 1.8
DUART, system control, I2C, SPI, JTAG	42	OV_{DD} = 3.3
GPIO signals	42	OV_{DD} = 3.3

2.1.4 Input Capacitance Specification

The following table describes the input capacitance for the SYS_CLK_IN pin in the MPC8306S.

Table 4. Input Capacitance Specification

Parameter/Condition	Symbol	Min	Max	Unit	Note
Input capacitance for all pins except SYS_CLK_IN and QE_CLK_IN	C_I	6	8	pF	—
Input capacitance for SYS_CLK_IN and QE_CLK_IN	C_{ICLK_IN}	10	—	pF	1

Note:
1. The external clock generator should be able to drive 10 pF.

2.2 Power Sequencing

The device does not require the core supply voltage (V_{DD}) and I/O supply voltages (GV_{DD} and OV_{DD}) to be applied in any particular order. Note that during power ramp-up, before the power supplies are stable and if the I/O voltages are supplied before the core voltage, there might be a period of time that all input and output pins are actively driven and cause contention and excessive current. In order to avoid actively driving the I/O pins and to eliminate excessive current draw, apply the core voltage (V_{DD}) before the I/O voltage (GV_{DD} and OV_{DD}) and assert $\overline{\text{PORESET}}$ before the power supplies fully ramp up. In the case where the core voltage is applied first, the core voltage supply must rise to 90% of its nominal value before the I/O supplies reach 0.7 V; see Figure 3. Once both the power supplies (I/O voltage and core voltage) are stable, wait for a minimum of 32 clock cycles before negating $\overline{\text{PORESET}}$.

NOTE

There is no specific power down sequence requirement for the device. I/O voltage supplies (GV_{DD} and OV_{DD}) do not have any ordering requirements with respect to one another.

4.2 AC Electrical Characteristics

The primary clock source for the MPC8306S is SYS_CLK_IN. The following table provides the clock input (SYS_CLK_IN) AC timing specifications for the MPC8306S. These specifications are also applicable for QE_CLK_IN.

Table 8. SYS_CLK_IN AC Timing Specifications

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Note
SYS_CLK_IN frequency	$f_{SYS\_CLK\_IN}$	24	—	66.67	MHz	1
SYS_CLK_IN cycle time	$t_{SYS\_CLK\_IN}$	15	—	41.6	ns	—
SYS_CLK_IN rise and fall time	t_{KH}, t_{KL}	1.1	—	2.8	ns	2
SYS_CLK_IN duty cycle	$t_{KHK}/t_{SYS\_CLK\_IN}$	40	—	60	%	3
SYS_CLK_IN jitter	—	—	—	±150	ps	4, 5

Notes:
1. **Caution:** The system, core and QUICC Engine block must not exceed their respective maximum or minimum operating frequencies.
2. Rise and fall times for SYS_CLK_IN are measured at 0.33 and 2.97 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. The SYS_CLK_IN driver's closed loop jitter bandwidth should be < 500 kHz at –20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track SYS_CLK_IN drivers with the specified jitter.
6. Spread spectrum is allowed up to 1% down-spread @ 33kHz (max rate).

5 RESET Initialization

This section describes the AC electrical specifications for the reset initialization timing requirements of the MPC8306S. The following table provides the reset initialization AC timing specifications for the reset component(s).

Table 9. RESET Initialization Timing Specifications

Parameter/Condition	Min	Max	Unit	Note
Required assertion time of $\overline{\text{HRESET}}$ to activate reset flow	32	—	$t_{SYS\_CLK\_IN}$	1
Required assertion time of PORESET with stable clock applied to SYS_CLK_IN	32	—	$t_{SYS\_CLK\_IN}$	1
$\overline{\text{HRESET}}$ assertion (output)	512	—	$t_{SYS\_CLK\_IN}$	1
Input setup time for POR configuration signals (CFG_RESET_SOURCE[0:3]) with respect to negation of $\overline{\text{PORESET}}$	4	—	$t_{SYS\_CLK\_IN}$	1, 2
Input hold time for POR config signals with respect to negation of $\overline{\text{HRESET}}$	0	—	ns	1, 2

Notes:
1. $t_{SYS\_CLK\_IN}$ is the clock period of the input clock applied to SYS_CLK_IN. For more details, see the *MPC8306S PowerQUICC II Pro Integrated Communications Processor Family Reference Manual*.
2. POR configuration signals consist of CFG_RESET_SOURCE[0:3].

Table 12. DDR2 SDRAM DC Electrical Characteristics for GV_{DD}(typ) = 1.8 V (continued)

Parameter/Condition	Symbol	Min	Max	Unit	Note
Output high current (V_{OUT} = 1.35 V)	I_{OH}	–13.4	—	mA	—
Output low current (V_{OUT} = 0.280 V)	I_{OL}	13.4	—	mA	—

Notes:
1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. MVREF is expected to be equal to 0.5 × GV_{DD}, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on MVREF may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to MVREF. This rail should track variations in the DC level of MVREF.
4. Output leakage is measured with all outputs disabled, 0 V ≤ V_{OUT} ≤ GV_{DD}.

The following table provides the DDR2 capacitance when GV_{DD}(typ) = 1.8 V.

Table 13. DDR2 SDRAM Capacitance for GV_{DD}(typ) = 1.8 V

Parameter/Condition	Symbol	Min	Max	Unit	Note
Input/output capacitance: DQ, DQS	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS	C_{DIO}	—	0.5	pF	1

Note:
1. This parameter is sampled. GV_{DD} = 1.8 V ± 0.100 V, f = 1 MHz, T_A = 25 °C, V_{OUT} = GV_{DD} ÷ 2, V_{OUT} (peak-to-peak) = 0.2 V.

6.2 DDR2 SDRAM AC Electrical Characteristics

This section provides the AC electrical characteristics for the DDR2 SDRAM interface.

6.2.1 DDR2 SDRAM Input AC Timing Specifications

This table provides the input AC timing specifications for the DDR2 SDRAM (GV_{DD}(typ) = 1.8 V).

Table 14. DDR2 SDRAM Input AC Timing Specifications for 1.8-V Interface

At recommended operating conditions with GV_{DD} of 1.8 V± 100mV.

Parameter	Symbol	Min	Max	Unit	Note
AC input low voltage	V_{IL}	—	MVREF – 0.25	V	—
AC input high voltage	V_{IH}	MVREF + 0.25	—	V	—

The following table provides the input AC timing specifications for the DDR2 SDRAM interface.

Table 15. DDR2 SDRAM Input AC Timing Specifications

At recommended operating conditions with GV_{DD} of 1.8V ± 100mV.

Parameter	Symbol	Min	Max	Unit	Note
Controller skew for MDQS—MDQ/MDM	t_{CISKEW}			ps	1, 2

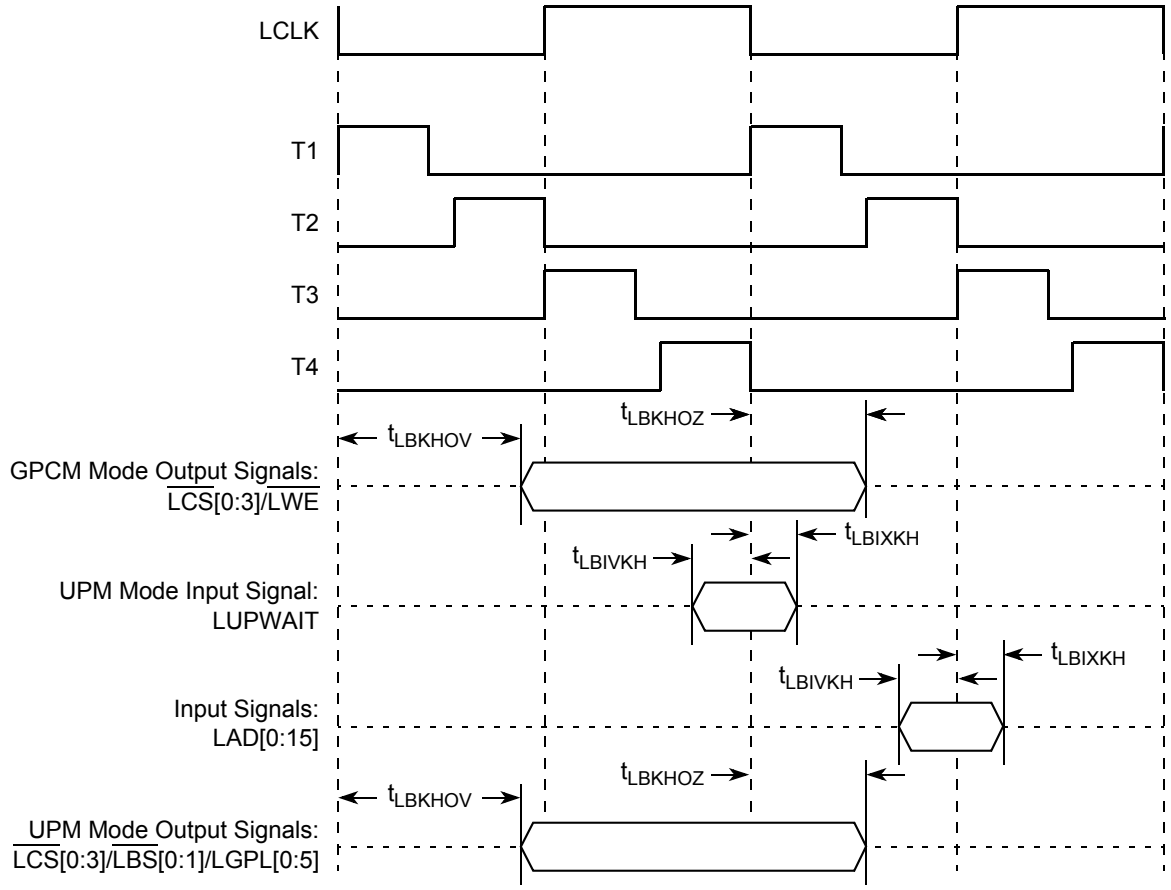


Figure 10. Local Bus Signals, GPCM/UPM Signals for LCRR[CLKDIV] = 4

8 Ethernet and MII Management

This section provides the AC and DC electrical characteristics for Ethernet interfaces.

8.1 Ethernet Controller (10/100 Mbps)—MII/RMII Electrical Characteristics

The electrical characteristics specified here apply to all MII (media independent interface) and RMII (reduced media independent interface), except MDIO (management data input/output) and MDC (management data clock). The MII and RMII are defined for 3.3 V. The electrical characteristics for MDIO and MDC are specified in Section 8.3, "Ethernet Management Interface Electrical Characteristics."

8.1.1 DC Electrical Characteristics

All MII and RMII drivers and receivers comply with the DC parametric attributes specified in The following table.

The following figure shows the MII receive AC timing diagram.

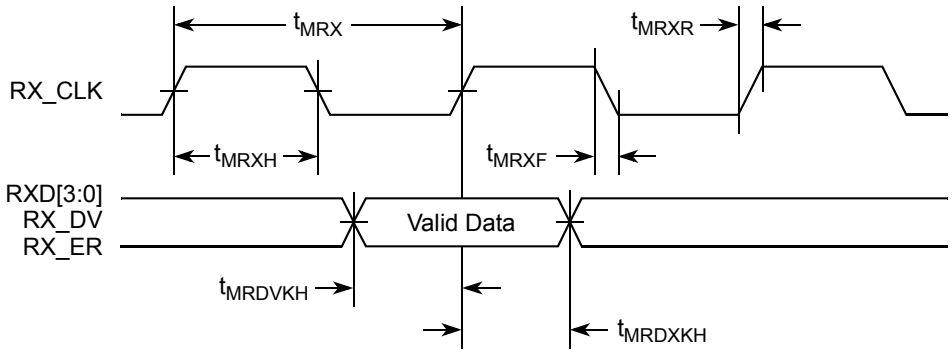


Figure 13. MII Receive AC Timing Diagram

8.2.2 RMII AC Timing Specifications

This section describes the RMII transmit and receive AC timing specifications.

8.2.2.1 RMII Transmit AC Timing Specifications

The following table provides the RMII transmit AC timing specifications.

Table 22. RMII Transmit AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 300mV.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit
REF_CLK clock	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%
REF_CLK to RMII data TXD[1:0], TX_EN delay	$t_{RMTKHDX}$	2	—	13	ns
REF_CLK data clock rise V_{IL}(min) to V_{IH}(max)	t_{RMXR}	1.0	—	4.0	ns
REF_CLK data clock fall V_{IH}(max) to V_{IL}(min)	t_{RMXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first three letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{RMTKHDX}$ symbolizes RMII transmit timing (RMT) for the time t_{RMX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII(RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

The following figure provides the AC test load.

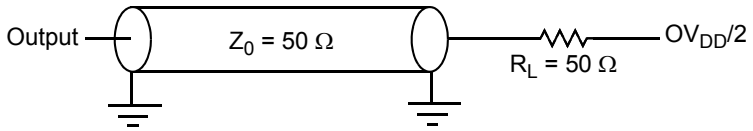


Figure 14. AC Test Load

The following figure shows the RMII receive AC timing diagram.

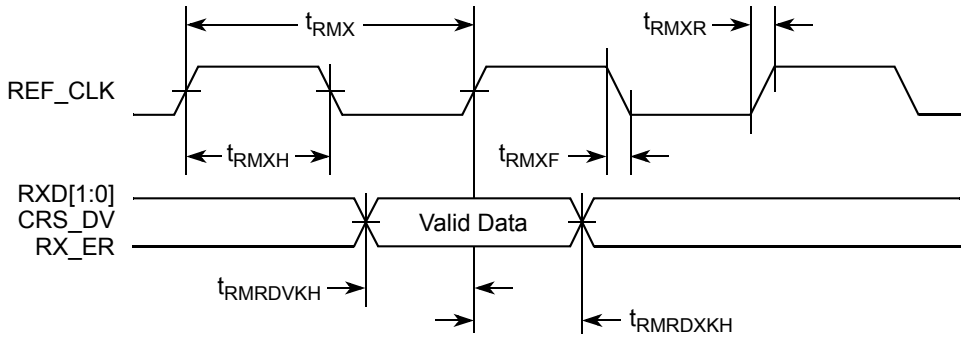


Figure 16. RMII Receive AC Timing Diagram

8.3 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals MDIO (management data input/output) and MDC (management data clock). The electrical characteristics for MII, and RMII are specified in Section 8.1, "Ethernet Controller (10/100 Mbps)—MII/RMII Electrical Characteristics."

8.3.1 MII Management DC Electrical Characteristics

MDC and MDIO are defined to operate at a supply voltage of 3.3 V. The DC electrical characteristics for MDIO and MDC are provided in the following table.

Table 24. MII Management DC Electrical Characteristics When Powered at 3.3 V

Parameter	Symbol	Conditions		Min	Max	Unit
Supply voltage (3.3 V)	OV_{DD}	—		3	3.6	V
Output high voltage	V_{OH}	I_{OH} = –1.0 mA	OV_{DD} = Min	2.40	OV_{DD} + 0.3	V
Output low voltage	V_{OL}	I_{OL} = 1.0 mA	OV_{DD} = Min	GND	0.50	V
Input high voltage	V_{IH}	—		2.00	—	V
Input low voltage	V_{IL}	—		—	0.80	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$		—	±5	μA

8.3.2 MII Management AC Electrical Specifications

The following table provides the MII management AC timing specifications.

Table 25. MII Management AC Timing Specifications

At recommended operating conditions with OV_{DD} is 3.3 V ± 300mV.

Parameter/Condition	Symbol[1]	Min	Typical	Max	Unit	Note
MDC frequency	f_{MDC}	—	2.5	—	MHz	—
MDC period	t_{MDC}	—	400	—	ns	—
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interface of the MPC8306S.

13.1 I²C DC Electrical Characteristics

The following table provides the DC electrical characteristics for the I²C interface of the MPC8306S.

Table 34. I²C DC Electrical Characteristics

At recommended operating conditions with OV_{DD} of 3.3 V ± 300mV.

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times OV_{DD}$	$OV_{DD} + 0.3$	V	—
Input low voltage level	V_{IL}	–0.3	$0.3 \times OV_{DD}$	V	—
Low level output voltage	V_{OL}	0	0.4	V	1
Output fall time from V_{IH}(min) to V_{IL}(max) with a bus capacitance from 10 to 400 pF	t_{I2KLKV}	$20 + 0.1 \times C_B$	250	ns	2
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	3
Capacitance for each I/O pin	C_I	—	10	pF	—
Input current ($0 V \le V_{IN} \le OV_{DD}$)	I_{IN}	—	±5	μA	4

Notes:
1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. C_B = capacitance of one bus line in pF.
3. Refer to the *MPC8306S PowerQUICC II Pro Integrated Communications Processor Family Reference Manual* for information on the digital filter used.
4. I/O pins obstructs the SDA and SCL lines if OV_{DD} is switched off.

13.2 I²C AC Electrical Specifications

The following table provides the AC timing parameters for the I²C interface of the MPC8306S.

Table 35. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 34).

Parameter	Symbol[1]	Min	Max	Unit
SCL clock frequency	f_{I2C}	0	400	kHz
Low period of the SCL clock	t_{I2CL}	1.3	—	μs
High period of the SCL clock	t_{I2CH}	0.6	—	μs
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	μs
Data setup time	t_{I2DVKH}	100	—	ns
Data hold time: I²C bus devices	t_{I2DXKL}	300	0.9[3]	μs
Rise time of both SDA and SCL signals	t_{I2CR}	$20 + 0.1\ C_B$[4]	300	ns

Table 35. I²C AC Electrical Specifications (continued)

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 34).

Parameter	Symbol[1]	Min	Max	Unit
Fall time of both SDA and SCL signals	t_{I2CF}	20 + 0.1 C_B[4]	300	ns
Setup time for STOP condition	t_{I2PVKH}	0.6	—	μs
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μs
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	0.1 × OV_{DD}	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	0.2 × OV_{DD}	—	V

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. MPC8306S provides a hold time of at least 300 ns for the SDA signal (referred to the V_{IH}(min) of the SCL signal) to bridge the undefined region of the falling edge of SCL.
3. The maximum t_{I2DVKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. C_B = capacitance of one bus line in pF.

The following figure provides the AC test load for the I²C.

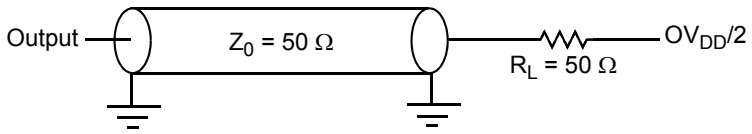


Figure 25. I²C AC Test Load

The following figure shows the AC timing diagram for the I²C bus.

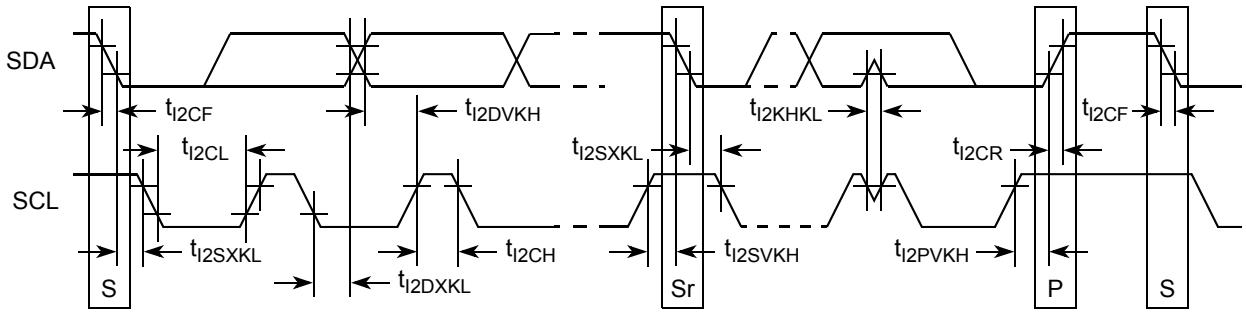
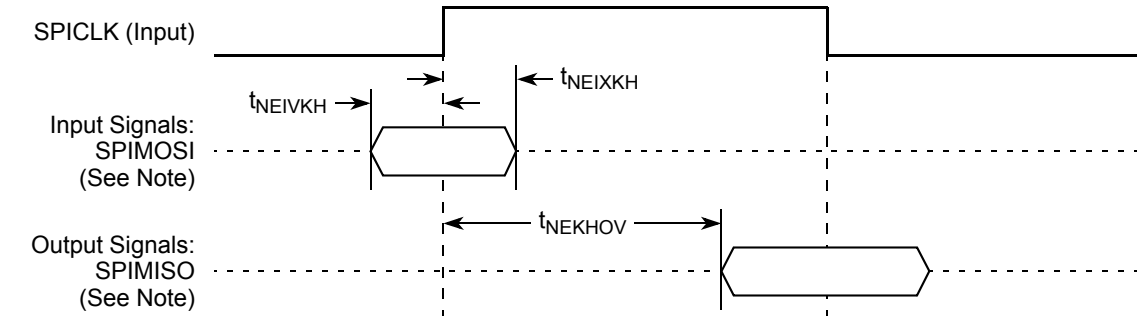


Figure 26. I²C Bus AC Timing Diagram

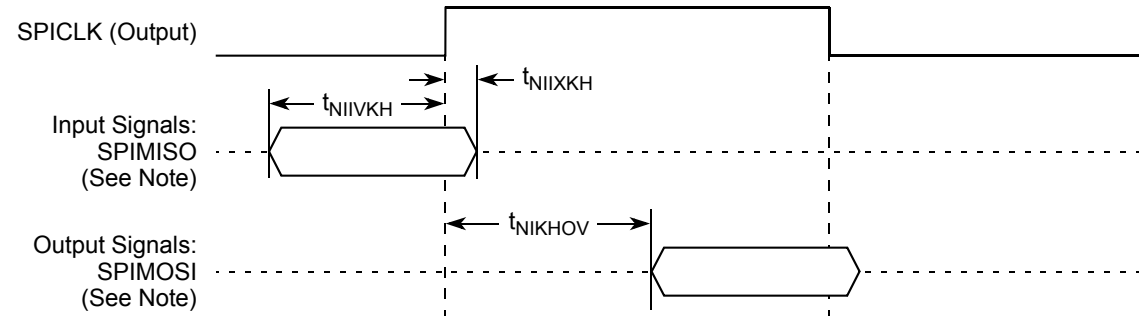
The following figure shows the SPI timing in slave mode (external clock).



Note: The clock edge is selectable on SPI.

Figure 30. SPI AC Timing in Slave Mode (External Clock) Diagram

The following figure shows the SPI timing in master mode (internal clock).



Note: The clock edge is selectable on SPI.

Figure 31. SPI AC Timing in Master Mode (Internal Clock) Diagram

18 JTAG

This section describes the DC and AC electrical specifications for the IEEE Std. 1149.1™ (JTAG) interface of the MPC8306S.

18.1 JTAG DC Electrical Characteristics

The following table provides the DC electrical characteristics for the IEEE Std. 1149.1 (JTAG) interface of the MPC8306S.

Table 44. JTAG Interface DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –6.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 6.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V

Table 44. JTAG Interface DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.0	OV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le OV_{DD}$	—	±5	μA

18.2 JTAG AC Electrical Characteristics

This section describes the AC electrical specifications for the IEEE Std. 1149.1 (JTAG) interface of the MPC8306S. The following table provides the JTAG AC timing specifications as defined in Figure 33 through Figure 36.

Table 45. JTAG AC Timing Specifications (Independent of SYS_CLK_IN)[1]

At recommended operating conditions (see Table 2).

Parameter	Symbol[2]	Min	Max	Unit	Notes
JTAG external clock frequency of operation	f_{JTG}	0	33.3	MHz	—
JTAG external clock cycle time	t_{JTG}	30	—	ns	—
JTAG external clock pulse width measured at 1.4 V	t_{JTKHKL}	11	—	ns	—
JTAG external clock rise and fall times	t_{JTGR}, t_{JTGF}	0	2	ns	—
$\overline{\text{TRST}}$ assert time	t_{TRST}	25	—	ns	3
Input setup times: Boundary-scan data TMS, TDI	 t_{JTDVKH} t_{JTIVKH}	 4 4	 — —	ns	4
Input hold times: Boundary-scan data TMS, TDI	 t_{JTDXKH} t_{JTIXKH}	 10 10	 — —	ns	4
Valid times: Boundary-scan data TDO	 t_{JTKLDV} t_{JTKLOV}	 2 2	 15 15	ns	5

Table 46. MPC8306S Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
USBDR_TXDRXD[7]/GPIO[37]/QE_BRG[11]	Y5	IO	OV_{DD}	—
DUART				
UART1_SOUT[1]/LSRCID4/LCS_B[4]	C23	O	OV_{DD}	—
UART1_SIN[1]/LDVAL/LCS_B[5]	F19	IO	OV_{DD}	—
UART1_SOUT[2]/UART1_RTS_B1/LCS_B[6]	D23	O	OV_{DD}	—
UART1_SIN[2]/UART1_CTS_B[1]/LCS_B[7]	D22	IO	OV_{DD}	—
Interrupts				
IRQ_B0_MCP_IN_B/CE_PI_0	E20	IO	OV_{DD}	—
IRQ_B1/MCP_OUT_B	E23	IO	OV_{DD}	—
IRQ_B2/CKSTOP_OUT_B	E22	IO	OV_{DD}	—
IRQ_B3/CKSTOP_IN_B	F20	I	OV_{DD}	—
I2C / SPI				
IIC_SDA1	G20	IO	OV_{DD}	2
IIC_SCL1	J20	IO	OV_{DD}	2
LCLK1/IIC_SCL2/CKSTOP_IN_B	H20	IO	OV_{DD}	2
SPISEL_BOOT/IIC_SDA2/CKSTOP_OUT_B	F23	O	OV_{DD}	2
SPIMOSI/LSRCID[2]	G22	IO	OV_{DD}	—
SPIMISO/LSRCID[3]	K20	IO	OV_{DD}	—
SPICLK/LSRCID[0]	G23	IO	OV_{DD}	—
SPISEL/LSRCID[1]	H22	I	OV_{DD}	—
FEC Management				
FEC_MDC	H23	O	OV_{DD}	—
FEC_MDIO	L20	IO	OV_{DD}	—
FEC1/GTM/GPIO				
FEC1_COL/GTM1_TIN[1]/GPIO[16]	AB20	IO	OV_{DD}	—
FEC1_CRS/GTM1_TGATE1_B/GPIO[17]	AC21	IO	OV_{DD}	—
FEC1_RX_CLK/GPIO[18]	Y17	IO	OV_{DD}	—
FEC1_RX_DV/GTM1_TIN[2]/GPIO[19]	Y18	IO	OV_{DD}	—
FEC1_RX_ER/GTM1_TGATE[2]_B/GPIO[20]	AB19	IO	OV_{DD}	—
FEC1_RXD0/GPIO[21]	AC20	IO	OV_{DD}	—
FEC1_RXD1/GTM1_TIN[3]/GPIO[22]	AC19	IO	OV_{DD}	—
FEC1_RXD2/GTM1_TGATE[3]_B/GPIO[23]	AC18	IO	OV_{DD}	—
FEC1_RXD3/GPIO[24]	AB17	IO	OV_{DD}	—
FEC1_TX_CLK/GTM1_TIN4/GPIO[25]	Y15	IO	OV_{DD}	—
FEC1_TX_EN/GTM1_TGATE[4]_B/GPIO[26]	Y16	IO	OV_{DD}	—

20.1 System Clock Domains

As shown in Figure 38, the primary clock input (frequency) is multiplied up by the system phase-locked loop (PLL) and the clock unit to create four major clock domains:

- The coherent system bus clock (*csb_clk*)
- The QUICC Engine clock (*qe_clk*)
- The internal clock for the DDR controller (*ddr_clk*)
- The internal clock for the local bus controller (*lbc_clk*)

The *csb_clk* frequency is derived from the following equation:

$$\textbf{\textit{csb\_clk}} = \textbf{SYS\_CLK\_IN} \times \textbf{SPMF} \qquad \textbf{\textit{Eqn. 1}}$$

The *csb_clk* serves as the clock input to the e300 core. A second PLL inside the core multiplies up the *csb_clk* frequency to create the internal clock for the core (*core_clk*). The system and core PLL multipliers are selected by the SPMF and COREPLL fields in the reset configuration word low (RCWL) which is loaded at power-on reset or by one of the hard-coded reset options. For more information, see the Reset Configuration chapter in the *MPC8306S PowerQUICC II Pro Integrated Communications Processor Family Reference Manual*.

The *qe_clk* frequency is determined by the QUICC Engine PLL multiplication factor (RCWL[CEPMF]) and the QUICC Engine PLL division factor (RCWL[CEPDF]) as the following equation:

$$\text{qe\_clk} = (\text{QE\_CLK\_IN} \times \text{CEPMF}) \div (1 + \text{CEPDF}) \qquad \textbf{Eqn. 2}$$

$$\textbf{\textit{qe\_clk = (QE\_CLK\_IN} \times \textit{CEPMF) } \div \textit{ (1 + CEPDF)}} \qquad \textbf{\textit{Eqn. 3}}$$

For more information, see the QUICC Engine PLL Multiplication Factor section and the “QUICC Engine PLL Division Factor” section in the *MPC8306S PowerQUICC II Pro Integrated Communications Processor Family Reference Manual* for more information.

The DDR SDRAM memory controller operates with a frequency equal to twice the frequency of *csb_clk*. Note that *ddr_clk* is not the external memory bus frequency; *ddr_clk* passes through the DDR clock divider (÷2) to create the differential DDR memory bus clock outputs (MCK and $\overline{\text{MCK}}$). However, the data rate is the same frequency as *ddr_clk*.

The local bus memory controller operates with a frequency equal to the frequency of *csb_clk*. Note that *lbc_clk* is not the external local bus frequency; *lbc_clk* passes through the LBC clock divider to create the external local bus clock outputs (LCLK). The LBC clock divider ratio is controlled by LCRR[CLKDIV]. For more information, see the LBC Bus Clock and Clock Ratios section in the *MPC8306S PowerQUICC II Pro Integrated Communications Processor Family Reference Manual*.

Table 52. QUICC Engine PLL Multiplication Factors (continued)

RCWL[CEPMF]	RCWL[CEPDF]	QUICC Engine PLL Multiplication Factor = RCWL[CEPMF]/ (1 + RCWL[CEPDF)
00111	0	× 7
01000	0	× 8
01001–11111	0	Reserved

The RCWL[CEVCOD] denotes the QUICC Engine PLL VCO internal frequency as shown in the following table.

Table 53. QUICC Engine PLL VCO Divider

RCWL[CEVCOD]	VCO Divider
00	2
01	4
10	8
11	Reserved

NOTE

The VCO divider (RCWL[CEVCOD]) must be set properly so that the QUICC Engine VCO frequency is in the range of 300–600 MHz. The QUICC Engine frequency is not restricted by the CSB and core frequencies. The CSB, core, and QUICC Engine frequencies should be selected according to the performance requirements.

The QUICC Engine VCO frequency is derived from the following equations:

qe_clk = (primary clock input × CEPMF) ÷ (1 + CEPDF)

QUICC Engine VCO Frequency = *qe_clk* × VCO divider × (1 + CEPDF)

20.5 Suggested PLL Configurations

To simplify the PLL configurations, the MPC8306S might be separated into two clock domains. The first domain contains the CSB PLL and the core PLL. The core PLL is connected serially to the CSB PLL, and has the csb_clk as its input clock. The second clock domain has the QUICC Engine PLL. The clock domains are independent, and each of their PLLs is configured separately.

The following table shows suggested PLL configurations for 33 and 66 MHz input clocks.

Table 54. Suggested PLL Configurations

Conf No.	SPMF	Core PLL	CEPMF	CEDF	Input Clock Frequency (MHz)	CSB Frequency (MHz)	Core Frequency (MHz)	QUICC Engine Frequency (MHz)
1	0100	0000100	0111	0	33.33	133.33	266.66	233
2	0010	0000100	0111	1	66.67	133.33	266.66	233
3	0100	0000101	0111	0	33.33	133.33	333.33	233
4	0101	0000101	1001	0	25	125	312.5	225
5	0010	0000101	0111	1	66.67	133.33	333.33	233

T_A = ambient temperature for the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

P_D = power dissipation in the package (W)

The junction-to-ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. As a general statement, the value obtained on a single layer board is appropriate for a tightly packed printed-circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated. Test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

21.1.3 Estimation of Junction Temperature with Junction-to-Board Thermal Resistance

The thermal performance of a device cannot be adequately predicted from the junction-to-ambient thermal resistance. The thermal performance of any component is strongly dependent on the power dissipation of surrounding components. In addition, the ambient temperature varies widely within the application. For many natural convection and especially closed box applications, the board temperature at the perimeter (edge) of the package is approximately the same as the local air temperature near the device. Specifying the local ambient conditions explicitly as the board temperature provides a more precise description of the local ambient conditions that determine the temperature of the device.

At a known board temperature, the junction temperature is estimated using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D) \qquad \textit{Eqn. 2}$$

where:

T_J = junction temperature (°C)

T_B = board temperature at the package perimeter (°C)

$R_{\theta JB}$ = junction-to-board thermal resistance (°C/W) per JESD51-8

P_D = power dissipation in package (W)

When the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. The application board should be similar to the thermal test condition: the component is soldered to a board with internal planes.

21.1.4 Experimental Determination of Junction Temperature

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D) \qquad \textit{Eqn. 3}$$

where:

T_J = junction temperature (°C)

22.2 PLL Power Supply Filtering

Each of the PLLs listed above is provided with power through independent power supply pins. The voltage level at each $AV_{DD}n$ pin should always be equivalent to V_{DD}, and preferably these voltages are derived directly from V_{DD} through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits as illustrated in Figure 41, one to each of the three AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum effective series inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in *High Speed Digital Design: A Handbook of Black Magic* (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of package, without the inductance of vias.

The following figure shows the PLL power supply filter circuit.

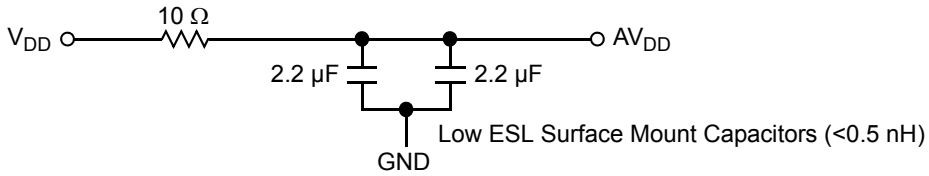


Figure 41. PLL Power Supply Filter Circuit

22.3 Decoupling Recommendations

Due to large address and data buses, and high operating frequencies, the MPC8306S can generate transient power surges and high frequency noise in its power supply, especially while driving large capacitive loads. This noise must be prevented from reaching other components in the MPC8306S system, and MPC8306S itself requires a clean, tightly regulated source of power. Therefore, it is recommended that the system designer place at least one decoupling capacitor at each V_{DD}, OV_{DD}, and GV_{DD} pins of the MPC8306S. These decoupling capacitors should receive their power from separate V_{DD}, OV_{DD}, GV_{DD}, and GND power planes in the PCB, utilizing short traces to minimize inductance. Capacitors may be placed directly under the device using a standard escape pattern. Others may surround the part.

These capacitors should have a value of 0.01 or 0.1 µF. Only ceramic SMT (surface mount technology) capacitors should be used to minimize lead inductance, preferably 0402 or 0603 sizes.

In addition, it is recommended that there be several bulk storage capacitors distributed around the PCB, feeding the V_{DD}, OV_{DD}, and GV_{DD} planes, to enable quick recharging of the smaller chip capacitors. These bulk capacitors should have a low ESR (equivalent series resistance) rating to ensure the quick response time necessary. They should also be connected to the power and ground planes through two vias

to minimize inductance. Suggested bulk capacitors—100 to 330 µF (AVX TPS tantalum or Sanyo OSCON).

22.4 Output Buffer DC Impedance

For all buses, the driver is a push-pull single-ended driver type (open drain for I^2C).

To measure Z_0 for the single-ended drivers, an external resistor is connected from the chip pad to OV_{DD} or GND. Then, the value of each resistor is varied until the pad voltage is $OV_{DD}/2$ (see Figure 42). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open) and R_P is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

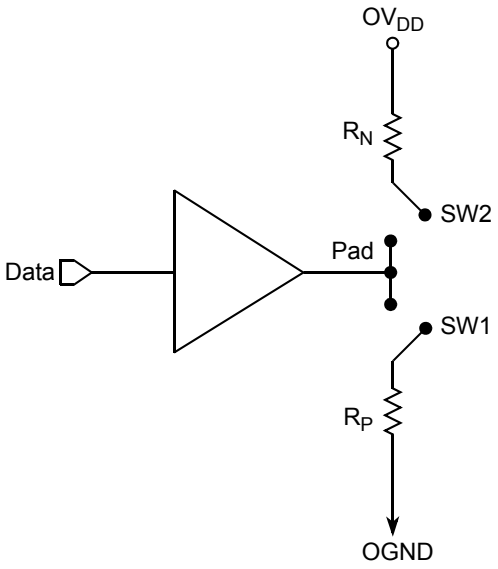


Figure 42. Driver Impedance Measurement

The value of this resistance and the strength of the driver's current source can be found by making two measurements. First, the output voltage is measured while driving logic 1 without an external differential termination resistor. The measured voltage is $V_1 = R_{source} \times I_{source}$. Second, the output voltage is measured while driving logic 1 with an external precision differential termination resistor of value R_{term}. The measured voltage is $V_2 = (1/(1/R_1 + 1/R_2)) \times I_{source}$. Solving for the output impedance gives $R_{source} = R_{term} \times (V_1/V_2 - 1)$. The drive current is then $I_{source} = V_1/R_{source}$.

Table 57. Part Numbering Nomenclature

MPC	*nnnn*	*C*	*VM*	*AF*	*D*	*C*	*A*
Product Code	**Part Identifier**	**Temperature Range[1]**	**Package[2]**	**e300 Core Frequency[3]**	**DDR2 Frequency**	**QUICC Engine Frequency**	**Revision Level**
MPC	8306S	Blank = 0 to 105°C C = –40 to 105°C	VM = Pb-free	AB = 133MHz AC = 200 MHz AD = 266 MHz AF = 333 MHz	D = 266 MHz F = 333 MHz	C = 233 MHz	Contact local Freescale sales office

Notes:
1. Contact local Freescale office on availability of parts with C temperature range.
2. See Section 19, “Package and Pin Listings,” for more information on available package types.
3. Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by Part Number Specifications may support other maximum core frequencies.

23.2 Part Marking

Parts are marked as in the example shown in the following figure.

MAPBGA

Notes:
ATWLYYWW is the traceability code.
CCCCC is the country code.
MMMMM is the mask number.
YWWLAZ is the assembly traceability code.

Figure 43. Freescale Part Marking for MAPBGA Devices

The following table shows the SVR Settings.

Table 58. SVR Settings

Device	Package	SVR (Rev 1.0)	SVR (Rev 1.1)
MPC8306S	MAPBGA	0x8110_0210	0x8110_0211
Note: PVR = 0x8085_0020			

24 Document Revision History

The following table provides a revision history for this document.

Table 59. Document Revision History

Rev. No.	Date	Substantive Change(s)
1	09/2011	• Added Power numbers for core frequency of 333 MHz in Table 5. • Updated QUICC Engine frequency in Table 5. • Added SPISEL_BOOT in MPC8306 Pin out Listing Table 46. • Corrected SPISEL Pin Type in Table 46 • Updated QUICC Engine frequency from 200 MHz to 233 MHz in Table 48. • Added new PLL configurations as per new core frequency in Table 54. • Updated CEPMF and CEDF as per new QE frequency in Table 54. • Added AF to indicate 333 MHz in Table 57 • Updated QE Frequency to 233 MHz in Table 57.
0	03/2011	Initial Release

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